JOURNAL OF ELECTRONIC TESTING:
Theory and Applications
(JETTA)

Volume 39, Numbers 5–6, December 2023

SURVEY OF PCB TEST METHODS

TEST GENERATION

FAULT TOLERANCE

SINGLE EVENT UPSET (SEU)

ELECTROMAGNETIC INTERFERENCE (EMI)

HARDWARE SECURITY

SOFTWARE TESTING

Further articles can be found at link.springer.com

Indexed/abstracted in *ACM Digital Library, BFI List, Baidu, CLOCKSS, CNKI, CNPIEC, Current Contents Collections / Electronics & Telecommunications Collection, Current Contents/Engineering, Computing and Technology, DBLP, Dimensions, EBSCO Academic Search, EBSCO Discovery Service, EBSCO STM Source, EI Compendex, Google Scholar, INIS Atomindex, INSPEC, Japanese Science and Technology Agency (JST), Journal Citation Reports/ Science Edition, Naver, Norwegian Register for Scientific Journals and Series, OCLC WorldCat Discovery Service, Portico, ProQuest Abstracts in New Technologies and Engineering (ANTE), ProQuest Advanced Technologies & Aerospace Database, ProQuest Aluminium Industry Abstracts, ProQuest-ExLibris Primo, ProQuest-ExLibris Summon, SCImago, SCOPUS, Science Citation Index Expanded (SCIE), TD Net Discovery Service, UGC-CARE List (India), Wanfang*

Instructions for Authors for *J Electron Test* are available at www.springer.com/10836.

JOURNAL OF ELECTRONIC TESTING

Volume 39, Numbers 5–6, December 2023 535–678

Springer

JOURNAL OF ELECTRONIC TESTING
Theory and Applications (JETTA)

Editor in Chief: Vishwani Agrawal

A journal serving electronic test professionals in concurrence with the Test Technology Technical Council (TTTC) of the IEEE Computer Society

tttc™

Springer

ISSN: 0923-8174